

	Type	L #	Hits	Search Text	DBs
1	BRS	L1	235358	438/\$.ccls. 250/\$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
2	BRS	L2	308	1 and ((measur\$3 or detect\$3 or investigat\$3) near contamination)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
3	BRS	L3	135	2 and beam	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
4	BRS	L4	8	3 and (measur\$3 or differen\$3) near current	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
5	BRS	L5	2	4 and voltage near source	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
6	BRS	L6	172	(ushiki-takeo or yamada-keizo or itagaki-yohsuke or tsujide-tohru).in.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
7	BRS	L7	1	6 and ((measur\$3 or detect\$3 or analyz\$3 or investigat\$3) near contamination)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
8	BRS	L8	607	((measur\$3 or detect\$3 or analyz\$3 or investigat\$3) near contamination).ti.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
9	BRS	L10	2	9 and (measur\$3 or differen\$3) near current	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
10	BRS	L9	6	8 and (electron near (gun or beam))	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
11	BRS	L11	3031	((measur\$3 or detect\$3 or analyz\$3 or investigat\$3) near contamination)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
12	BRS	L12	86	11 and (measur\$3 or differen\$3) near current	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
13	BRS	L13	4	12 and.(constant near voltage)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
14	BRS	L14	37	12 and (beam or radiat\$3)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
15	BRS	L16	1	15 and movable near (stage or sample or substrate)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
16	BRS	L15	20	14 and chamber	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB
17	BRS	L17	11	12 and reference near (current or sample)	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB